Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/064,251	LI ET AL.	
Examiner	. Art Unit	_
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SEARCHED				
Class	Subclass	Date	Examiner	
370	221-223	8/24/2007	НМ	
370	216-218	8/24/2007	НМ	
370	225,227	8/24/2007	НМ	
370	228	8/24/2007	НМ	
370	241,242	8/24/2007	НМ	
370	244	8/24/2007	НМ	
. 370	250,400	8/24/2007	НМ	
370	401,406	8/24/2007	НМ	
714	100,1,2	8/24/2007	НМ	
709	239	8/24/2007	НМ	
379	221.1	8/24/2007	НМ	
379	221.04	8/24/2007	НМ	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Searched East DB:USPAT, UPGPUB, JPO, EPO	8/24/2007	НМ
IEEE	8/24/2007	нм
Palm Inventor's DB	8/24/2007	НМ
Consulted John Pezzlo (Primary) on search strategy and rejection strategy	8/24/2007	НМ
Consulted Doris (SPE) To on srejection strategy	8/28/2007	НМ
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